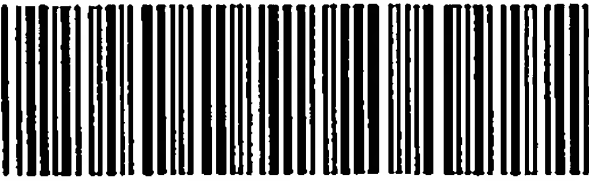


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/071,368	<b>Applicant(s)/Patent under Reexamination</b> HASEGAWA ET AL.	
	<b>Examiner</b> TUYEN T. NGUYEN	<b>Art Unit</b> 2832	

SEARCHED			
Class	Subclass	Date	Examiner
336	210-213, 233, 234	2/16/2005	TTN
148	304-306	2/16/2005	TTN
<i>updated</i>		<i>8/5/05</i>	<i>TTN</i>

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR